

Defect Definitions

Description	Definition	Class X Monochrome with microlens only	Class 0 Monochrome with microlens only	Class 1	Class 2 Color Only	Class 2 Monochrome Only	Notes	Test
Major dark field defective pixel	Defect \geq 239 mV	100	100	100	200	200	1,2	1
Major bright field defective pixel	Defect \geq 15 %						1,2	2
Minor dark field defective pixel	Defect \geq 123 mV	1000	1000	1000	2000	2000	1,2	1
Cluster defect	A group of 2 to "N" contiguous major defective pixels, but no more than "W" adjacent defects horizontally	0	1 N=10 W=3	20 N=10 W=3	20 N=10 W=3	20 N=12 W=5	1,2	
Column defect	A group of more than 10 contiguous major defective pixels along a single column	0	0	0	10	2	1,2	

Notes:

1. There will be at least two non-defective pixels separating any two major defective pixels.
2. Tested at 27°C and 40°C.

Class X sensors are offered strictly "as available". Kodak cannot guarantee delivery dates. Please call for availability.

Defect Map

The defect map supplied with each sensor is based upon testing at an ambient (27°C) temperature. Minor point defects are not included in the defect map. All defective pixels are reference to pixel 1,1 in the defect maps.